

# OFFICE OF THE COORDINATOR TEQIP III NATIONAL INSTITUTE OF TECHNOLOGY SRINAGAR

No.: NIT/TEQIP19/33

Date: 15/01/2019

## MINUTES OF MEETING

With reference to the "Invitation for bids for Multi Target Sputtering System" IBF No. TEQIP-III/nits/189 dated 26-11-2018; a Pre- Bid Conference was held at 14:30 hours on 15-01-2019 at the following venue:

**TEQIP III Conference Room  
National Institute of Technology Srinagar  
Hazratbal, Srinagar – 190006.**

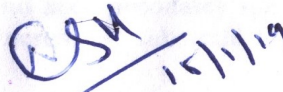
Following suppliers attended the pre bid conference:

1. Zubair Majid Khan representative of **SIAB Surgiments (karan Nagar Srinagar)**.
2. Nilesh Hardikar representative of **Harley Instruments Pune** on behalf of **Moorefield UK**.
3. A. Selva Kumar representative of **Hind High Vacuum Company (Community Centre, 3<sup>rd</sup> floor, East of Kailsh, New Delhi)**.

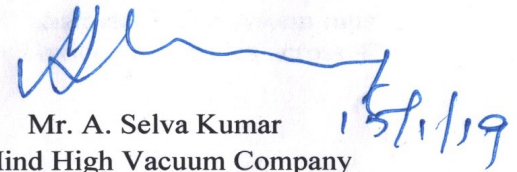
The revised technical specification can be found at Annexure A



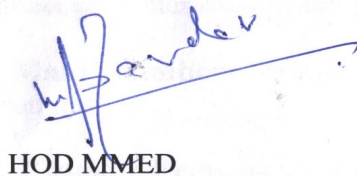
Mr. Zubair Majid Khan  
SIAB Surgiments



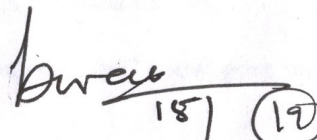
Mr. Nilesh Hardikar  
Harley Instruments



Mr. A. Selva Kumar  
Hind High Vacuum Company



HOD MMED



Prof. M.F. Wani  
(Chairman CRFC)



Dr. Shahid Saleem  
(Chairman Purchase Committee  
TEQIP III/NOP)

The revised  
Tech. specifications  
may pl. be got  
copy from  
Mr. Atikur Rahman  
16/1/19

## *Annexure A*

### REVISED TECHNICAL SPECIFICATIONS

#### **Main features of sputtering system:**

- 3” Dia Sputter source for con-focal, direct and off-axis deposition.
- Rotatable 4” substrate holders with substrate heater from Room Temperature to 800 °C with substrate bias.
- Chamber pressure in  $5 \times 10^{-7}$  mbar range or better with fast pump down times.
- Three 3” Diameter sputter guns with shutters capable of holding 3-inch Diameter targets With both head angle and height adjustment facility
  
- Capable of achieving uniformity +/- 3% across 4” substrate for metal, oxides & nitrides thin films
- PC or HMI based automated control at customer’s option.

#### **Description of sputtering system:**

##### **Sputtering system**

The sputtering system (100 Class clean room compatible) will be used for deposition of high quality, uniform metals and gate dielectric oxide ultrathin films. Turbo pump backed main chamber with vacuum in low  $10^{-7}$  mbar range (higher preferable) and turbo-pumped load lock chamber for fast pump down times. Three shuttered magnetron guns with Three inch diameter targets. It should be possible, dependent upon source configuration, to deposit magnetic and non-magnetic metals and insulators via both DC and/or RF power via a “sputter switch”. An optional co-deposition module should allow for DC/DC or RF/DC or DC/DC/RF sputtering simultaneously. Please note that all Co-Deposition from all 3 Magnetrons should also be possible in the above configuration.

Gases flow, chamber pressure, and substrate holder with motorized Z-motion for dynamic working distance control via the process control system for optimizing deposition conditions. Heated substrate holder that maintains temperature control from Room Temperature to 800°C before, during and/or after deposition. Substrate holder can be rotated and accommodates substrates 4” diameter. The system must be capable of achieving uniformity +/- 3% across 4” substrate for metals , oxides & nitrides across 4” substrate.

#### **Detailed Specifications for sputtering system:**

**i.** The equipment should be able to deposit any combination of metals, metal alloys, composites, semiconductors, insulators on semiconductor/glass/metal/alloy substrates in a single run as per the number of sputter sources and power supplies detailed herein.

**ii. Main chamber:** Stainless steel construction,  $\geq 4$ ” view port with load lock capable of handling 4” substrates.

**iii. Ultimate Pressure:**  $5 \times 10^{-7}$  mbar range or better. Stable Process Pressure during process better than +/-0.1 mbar during entire process and over the sputtering pressure range of 1E-3mb to 9E-3mb.

**iv. Vacuum Chamber:** SS, Cube Or D- shaped chamber (minimum chamber dimensions 400mm X400mm 400mm or more ) with load lock chamber capable of handling 4” diameter substrates.

The chamber should have 10 nos. of spare ports including an NW40CF for RGA. One number of view port with shutter arrangement on the front door is required. The chamber acts as sputtering chamber. It houses magnetron cathodes, substrate and shutter assembly etc. All the ports are fixed with Viton O-ring seal and matching flanges for vacuum integrity. The equipment should have water cooling arrangement to the magnetron sources to ensure uniform cooling of the target during sputter deposition. The chamber configuration is for sputter down geometry.

**v. Sputter cathodes:** Three of, three-inch target diameter sputter sources with auto shutters and shielding to prevent cross contamination. It should be possible to use all the 3 Sputter Guns with either RF Power Supply or DC Power Supply through an automated switch for deposition of: non-conductive, conductive or magnetic materials. The sputter sources should be compatible with magnetic materials in addition to conducting and non-conducting materials. Please note that 2 Magnetrons should be configured for Non-Magnetic materials while 1 magnetron should be configured for magnetic materials.

**vi. Load Lock chamber:** For loading and unloading of samples without breaking vacuum of process chamber. Separate vacuum pumping system required for load lock arrangement. Required capacity of Turbo molecular pump with suitable dry type backing/roughing pump. Please note that it should be possible to etch the substrate in the loadlock chamber using an RF Plasma via an automated procedure. All the necessary components to be able to RF etch the substrate before loading it for deposition should be included. Please note that the RF Plasma etch process should be fully automated & recipe driven.

**vii. Magnetron Source geometry:** The equipment should have three magnetron sputtering sources placed in a confocal configuration for multilayer deposition without breaking the vacuum **as standard. Co-Deposition Capability should also be offered.** The equipment should have provision to accommodate targets of 3" diameter. Changing of targets should be simple, quick and possible without breaking any internal seals. All the sources should be equipped with dedicated shutters. The quoted magnetron sources should be compatible with any of the DC, pulsed DC and RF power supply for con- focal, direct and off axis deposition.

**viii. Power Supplies:** One RF power supply of 300 Watt at frequency of 13.56 MHz with auto matching network (of reputed make, such as, SEREN/Advanced Energy/Comdel /T&C power conversion for both the RF generator and RF Matchbox) should be provided. One 1.5 KW DC power source (reputed SEREN/Advanced Energy/ Comdel/Glassman) make with automatic arc suppression (Documentation of Automatic Arc Suppression details from the original manufacturer should be included in the technical bid).

An interlocked, automated Software Controlled RF/DC switch (3 input channels and 5 output channels) to be supplied which can alternatively connect three magnetron sources to any of the 3 Power Supplies together with DC to the bias stage and RF to the etch stage.

**ix. Substrate fixture:** 4" Diameter Substrate holder with motorized Z-motion for working distance adjustment and substrate transfer hand off.

**x. Substrate Rotation:** The equipment should have provision so that the substrate holder can provide in situ rotation while heating (**0-30 rpm**).

**xi. Substrate Heater:** The equipment should have provision for substrate heating from Room Temperature to 800°C with PID control. The in vacuum heater parts used for substrate heating in item should be compatible with vacuum, plasma and a reactive environment. The heater element should be of SiC material.

**xii. Substrate Bias:** A Dedicated Separate DC Power Supply to provide a 0 to 500 V Substrate Bias to be provided. Please note that the DC Substrate bias will be used while deposition & will be controlled directly via software. The DC Bias supply should be routed via the sputter switch and be magnetron compatible.

**xiii. Thickness uniformity:**  $\leq \pm 3\%$  across the 4" substrate

**xiv. Vacuum pumping System:** Process chamber - High Vacuum pumping module should consist of a Turbo Molecular Pump of 400lit/sec or more , Dry scroll Pump 10m<sup>3</sup>/Hr or more, vacuum measuring gauges with all the necessary valves to have a fully automated pumping system. The pump down sequence as well as venting sequence should be fully automated & controlled via the PC or HMI Process Control. The basic system must be capable of giving vacuum order of  $5 \times 10^{-7}$  mbar or better. Pump should be Pfeiffer/ Leybold/Edwards make.

Load lock - High Vacuum pumping module should consist of a Turbo Molecular Pump of 80lit/sec or more , Dry scroll Pump 6m<sup>3</sup> /Hr or more, vacuum measuring gauges with all the necessary valves to have a fully automated pumping system. The pump down sequence as well as venting sequence should be fully automated & controlled via the PC or HMI Process Control. The basic system must be capable of giving vacuum order of  $5 \times 10^{-7}$  mbar or better and a pump down time to 2E-6mb of less than 20 minutes. Pump should be Pfeiffer/ Leybold/Edwards make.

Required water chillier with connection will be part vendor supply.

**xv. Valves:** All necessary valves to be able to have a fully automated pumping system should be included. Also, the necessary throttle valve to be able to control process pressure will have to be provided.

**xvi. Gauge Heads:** All gauges should be of Edwards/ Leybold / Pfeiffer/Granville Philips make. Necessary gauges for measurement of vacuum to be included in the system. Please note a Temperature Controlled Capacitance manometer should be included for measurement of process pressure & control. The process pressure control should be fully automated capable of controlling process pressure with a stability of  $\pm 0.1$  mbar. Please note that the process control should be fully automated.

**xvii. Gas Flow:** The equipment should comprise of three Mass Flow Controllers (of reputed make)with the option of a fourth, with power supply to control the flow of Argon, oxygen and nitrogen into the sputtering chamber. MFC lines should be leak tested to 1E-9mb. MFCs should deliver gas to the chamber via a manifold that allows for ratio mixing. Manifold should have a purge function to prevent memory effects run to run. Suitable gas channels (separate channel for each gas) are to be provided for argon, oxygen and nitrogen. MFC dynamic range to allow for process pressures from 1E-3mb to 1E-2mb and an O<sub>2</sub> to Ar ratio of up to 1:30

**xviii. Process Control:** PC based or automated, user friendly OS with recipe builder, data logging and report generation. The system should enable precise monitoring and control of film thickness and rate of deposition.

Appropriate fully automated pressure control should be offered as standard.

**xix. Supply of Sputtering Targets:** Oxides & Nitrides: Al<sub>2</sub>O<sub>3</sub>, Er<sub>2</sub>O<sub>3</sub>, HfO<sub>2</sub>, V<sub>2</sub>O<sub>5</sub>, VO<sub>2</sub>, ZrO<sub>2</sub>, TiO<sub>2</sub>, Fe<sub>2</sub>O<sub>3</sub>, TiN, PZT. Metals: W, Ti, Fe, Cu, Ni, Ta, Al, Cr, Co etc. Backing plate should quote wherever required.

**xx. Thickness controller:** Inficon make /SQC 310C with two film thickness monitor sensors (water cooling).

**xxi. Utility:**

- a. Electrical: Single Phase 220V /50Hz, 32 A, AC Power Supply
- b. Suitable Water Chiller will be supplied by the vendor
- c. Air: compressed air > 80 PSI.
- d. Process gases, high purity, dry gas at 25 psi, 100sccm flow rate
- e Vent gas – dry nitrogen at 5 psi

**IMPORTANT INSTRUCTIONS & ESSENTIAL CONDITIONS:**

- I. The vendor should provide a schematic diagram of the whole equipment clearly showing the configuration.
- II. The vendor should offer in case of successful bid, pre-delivery inspection of the equipment at their site for all the functionalities of the equipment as per the technical specifications mentioned in the tender document.
- III. A Compliance statement against each item mentioned in the technical specification must be provided in tabular format.
- IV. Warranty: The complete instrument and accessories excluding consumables should be under warranty for a period of two year from the date of installation. In case of breakdown during the warranty period, a competent service.
- V. The Bidder should have at least 5 systems with similar capabilities installed world-wide. They should have at least 1 customer in India with similar system specifications /capabilities. User Reference Details with Detailed address, telephone number as well as email address to be included in the bid.

Engineer of the supplier should make as many visits as are necessary to rectify the problem and replace the faulty parts. But it should be repaired within reasonable time from the date and time of complaint lodged by the user. The supplier should provide all spares required for making the instrument operational.

- VI. AMC: Please also mention the financial involvement for three years on site Annual Maintenance after normal warranty period separately as an additional offer.
- VII. Training and demonstration: Vendor should provide on-site demonstration of all the features of the system and training to operate the system should be arranged at no extra cost.
- VIII. Operating manual: One set of operating manual, service manual, maintenance and safety instructions, recommended recurring spare parts list, mechanical and electrical drawings, part lists, air, water and electrical diagrams should be provided with the instrument.